

FDP5680/FDB5680

60V N-Channel PowerTrench™ MOSFET

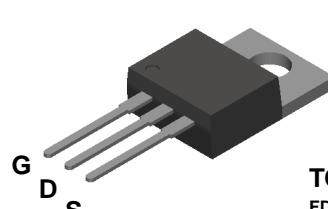
General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

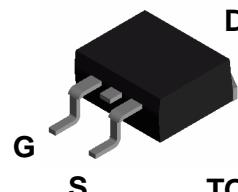
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{DS(on)}$ specifications resulting in DC/DC power supply designs with higher overall efficiency.

Features

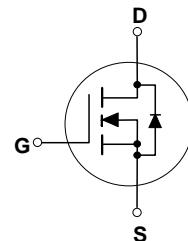
- 40 A, 60 V. $R_{DS(ON)} = 0.020 \Omega$ @ $V_{GS} = 10$ V
 $R_{DS(ON)} = 0.023 \Omega$ @ $V_{GS} = 6$ V.
- Critical DC electrical parameters specified at elevated temperature.
- Rugged internal source-drain diode can eliminate the need for an external Zener diode transient suppressor.
- High performance trench technology for extremely low $R_{DS(ON)}$.
- 175°C maximum junction temperature rating.



TO-220
FDP Series



TO-263AB
FDB Series



Absolute Maximum Ratings

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FDP5680	FDB5680	Units
V_{DSS}	Drain-Source Voltage	60		V
V_{GSS}	Gate-Source Voltage	± 20		V
I_D	Maximum Drain Current - Continuous	40		A
	- Pulsed	120		
P_D	Total Power Dissipation @ $T_C = 25^\circ\text{C}$	65		W
	Derate above 25°C	0.43		W/°C
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-65 to +175		°C

Thermal Characteristics

R_{JC}	Thermal Resistance, Junction-to-Case	2.3	°C/W
R_{JA}	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDB5680	FDB5680	13"	24mm	800
FDP5680	FDP5680	Tube	N/A	45

Electrical Characteristics $T_c = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Drain-Source Avalanche Ratings (Note1)						
W_{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 30\text{ V}$, $I_D = 40\text{ A}$			90	mJ
I_{AR}	Maximum Drain-Source Avalanche Current			40		A
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}$, $I_D = -250\text{ }\mu\text{A}$	60			V
ΔBV_{DSS} ΔT_J	Breakdown Voltage Temperature Coefficient	$I_D = -250\text{ }\mu\text{A}$, Referenced to 25°C		60		$\text{mV/}^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 48\text{ V}$, $V_{GS} = 0\text{ V}$			1	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$			100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20\text{ V}$, $V_{DS} = 0\text{ V}$			-100	nA
On Characteristics (Note 1)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	2	2.5	4	V
$\Delta V_{GS(th)}$ ΔT_J	Gate Threshold Voltage Temperature Coefficient	$I_D = -250\text{ }\mu\text{A}$, Referenced to 25°C		-6.4		$\text{mV/}^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}$, $I_D = 20\text{ A}$, $V_{GS} = 10\text{ V}$, $I_D = 20\text{ A}$, $T_J = 125^\circ\text{C}$ $V_{GS} = 6\text{ V}$, $I_D = 19\text{ A}$		0.016 0.022 0.018	0.020 0.035 0.023	Ω
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10\text{ V}$, $V_{DS} = 5\text{ V}$	20			A
g_{FS}	Forward Transconductance	$V_{DS} = 5\text{ V}$, $I_D = 20\text{ A}$		43		S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = 25\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1.0\text{ MHz}$		1850		pF
C_{oss}	Output Capacitance			230		pF
C_{rss}	Reverse Transfer Capacitance			95		pF
Switching Characteristics (Note 1)						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 30\text{ V}$, $I_D = 1\text{ A}$, $V_{GS} = 10\text{ V}$, $R_{GEN} = 6\text{ }\Omega$		15	27	ns
t_r	Turn-On Rise Time			9	18	ns
$t_{d(off)}$	Turn-Off Delay Time			35	56	ns
t_f	Turn-Off Fall Time			16	26	ns
Q_g	Total Gate Charge	$V_{DS} = 30\text{ V}$, $I_D = 20\text{ A}$ $V_{GS} = 10\text{ V}$		33	46	nC
Q_{gs}	Gate-Source Charge			6.5		nC
Q_{gd}	Gate-Drain Charge			7.5		nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain-Source Diode Forward Current	(Note 1)			40	A
V_{SD}	Drain-Source Diode Forward Voltage		$V_{GS} = 0\text{ V}$, $I_s = 20\text{ A}$	(Note 1)	0.9	1.2

Note:1. Pulse Test: Pulse Width $\leq 300\text{ }\mu\text{s}$, Duty Cycle $\leq 2.0\%$

Typical Characteristics

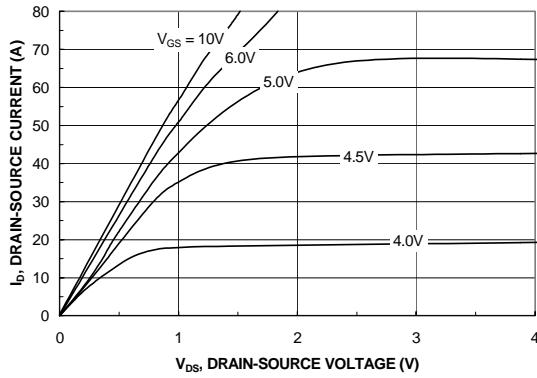


Figure 1. On-Region Characteristics.

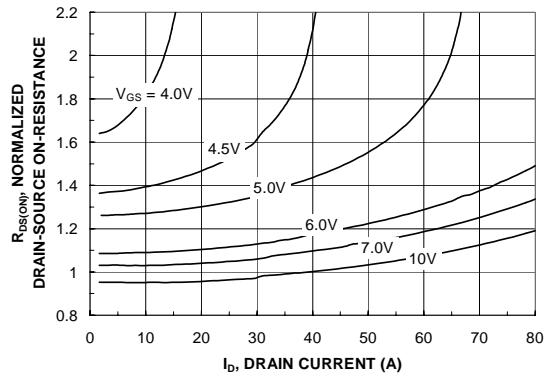


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

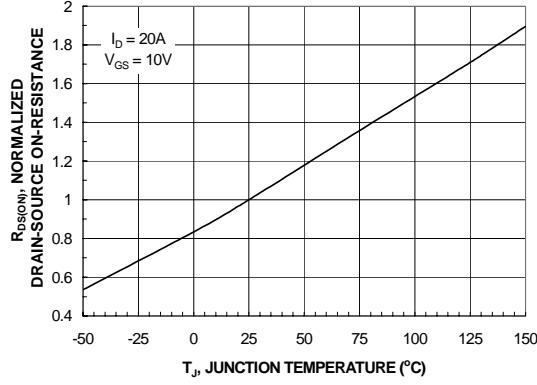


Figure 3. On-Resistance Variation with Temperature.

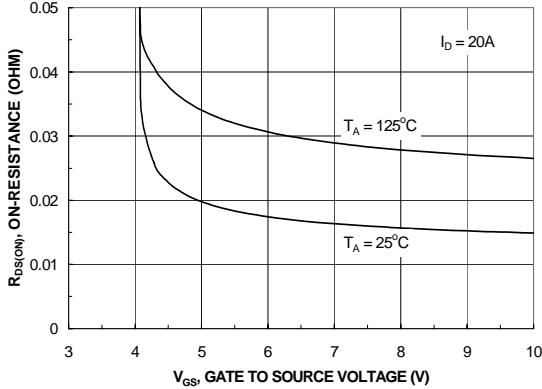


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

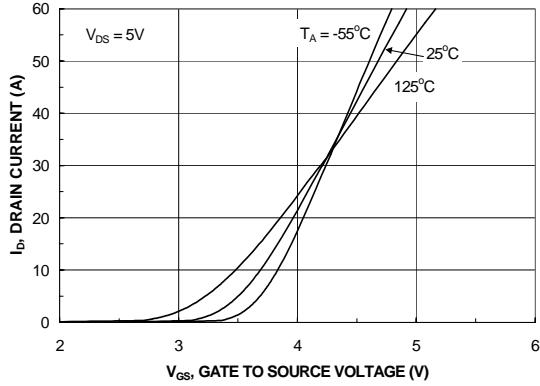


Figure 5. Transfer Characteristics.

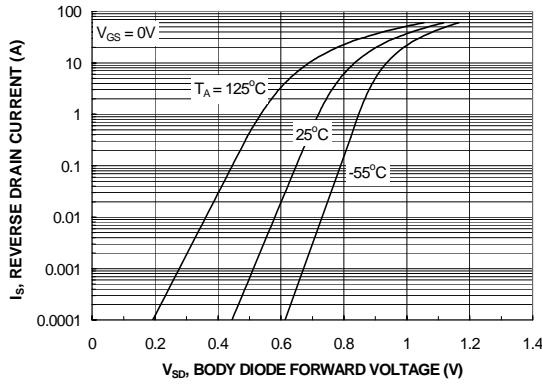


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)

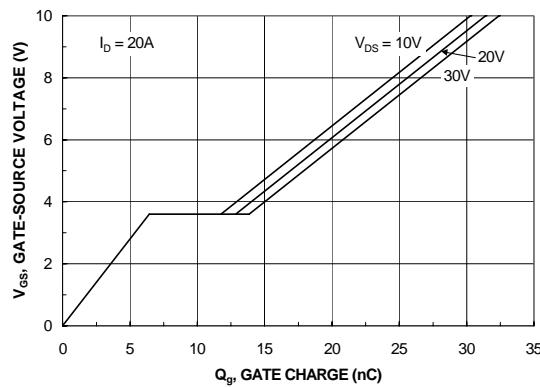


Figure 7. Gate-Charge Characteristics.

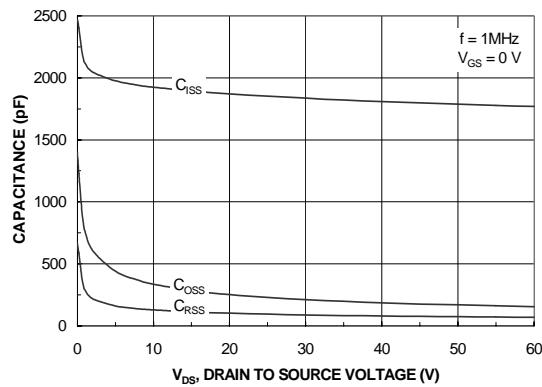


Figure 8. Capacitance Characteristics.

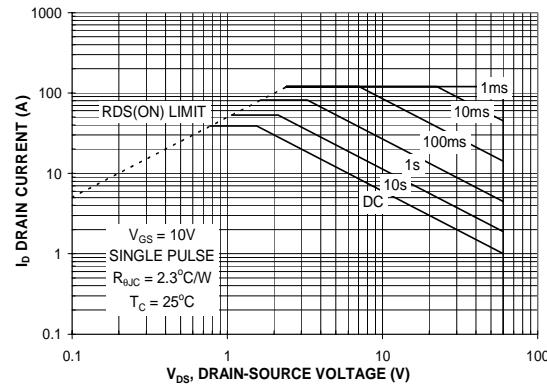


Figure 9. Maximum Safe Operating Area.

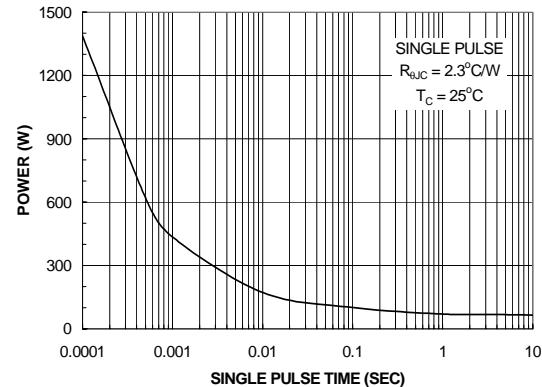


Figure 10. Single Pulse Maximum Power Dissipation.

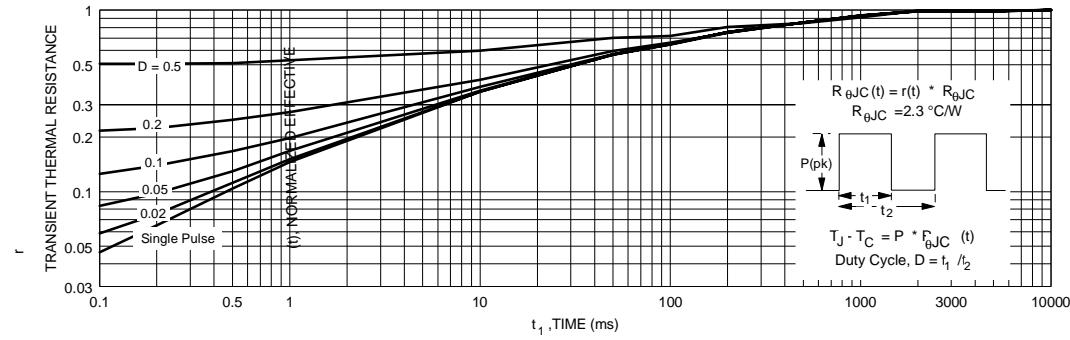


Figure 11. Transient Thermal Response Curve.

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